



FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE CITATION**
(Use several sheets if necessary)

Sheet 1 of 1

ATTORNEY DOCKET NO.	SERIAL NO.
9319S-000558	10/681,820
APPLICANT	
Nakano et al.	
FILING DATE	GROUP
October 8, 2003	2871

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.		6,215,538	4-10-2001	Narutaki et al.	349/106	1-25-1999
2.	Dw	2002-171791	11-21-2002	Anno et al.	349/113	3-26-2002

FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	Translation No
1.	Dw	1387074A	12/25/2005	China			X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.		Communication from Chinese Patent Office Re: counterpart application. NO ENGLISH

Examiner: *Dw/4EN*

Date Considered: *06/23/06*

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449)		ATTORNEY DOCKET NO.	SERIAL NO.
PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		9319S-000558	10/681,820
Sheet 1 of 1		APPLICANT	
		Tomoyuki Nakano	
		FILING DATE	GROUP
		October 8, 2003	2871

*NOV 29 2005
PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE CITATION*

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	<i>DR</i>	6,215,538	4/10/2001	Narutaki et al	349/106	—

FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes	Translation * No
1.	<i>DR</i>	2000-29012	1/28/2000	Japan	—	—	X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	<i>DR</i>	Communication from Korean Patent Office re: related application.

*One or more of the English translation documents submitted herewith may be Abstracts only or partial machine created translations from the Japanese Patent Office. As such, the submitter does not necessarily vouch for their accuracy. Additional information may be obtained from the Japanese Patent Office web site at www.jpo.go.jp

Examiner: *DR*

Date Considered:

10/23/06

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.